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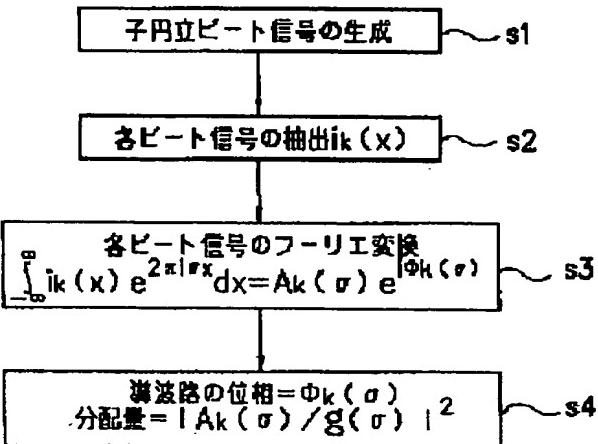
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TITLE : OPTICAL CIRCUIT EVALUATING
 METHOD



ABSTRACT : PURPOSE: To provide an optical circuit evaluating method, which can accurately measure phase change and optical power distribution quantity to be given to the light transmitting each optical wave guide path inside of an interference type optical circuit having optical wave guide paths at a different length from each other.

CONSTITUTION: A testing interference type optical circuit is located inside an interferometer using a light source having a coherent length shorter than a difference of the optical path length between any two optical wave guide paths of the optical circuit to generate the separate beat signal (s1), and each beat signal is extracted as a function of a difference of optical path length (s2), and Fourier transformation is performed (s3) to obtain each phase and each amplitude. Phase and optical power distribution quantity in each optical wave guide path is thereby obtained.

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